Se	arc	h N	lote	es	

Application/Control No.	Applicant(s)/Patent under Reexamination		
10/784,487	MOYER ET AL.	OYER ET AL.	
Examiner	Art Unit	Unit	_
Khanh B. Duong	2822	22	

SEARCHED				
Class Subclass		Date	Examiner	
			· 	

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
Interference Search Printout		7/23/2006	KBD	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
EAST update (text search: see search history printout)	7/23/2006	KBD	
Discussed with primary examiner Kevin Picardat	7/26/2006	KBD	
Inventor name search (PALM)	7/27/2006	KBD	